

1097 U.S. PTO
10/10/2001
1097/01

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10027639	12/19/2001	382	462.250	3621	SANDEK, A.

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225 2876

**CONTINUING DATA VERIFIED:

No

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** FOREIGN APPLICATIONS VERIFIED:

REPUBLIC OF KOREA 2001-2569 01/17/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiners's initials		<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no A	ATTORNEY DOCKET NO 9903-44
TITLE : Method and apparatus for detecting defective markings on a semiconductor product U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.	Print Fig.
TERMINAL DISCLAIMER		Primary Examiner		
		PREPARED FOR ISSUE		
		Application Examiner		
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